Abstracts

The Application of the Point Matching Method to the Analysis of Microstrip Lines with Finite Metallization Thickness

S. Kosslowski, F. Bogelsack and I. Wolff. "The Application of the Point Matching Method to the Analysis of Microstrip Lines with Finite Metallization Thickness." 1988 Transactions on Microwave Theory and Techniques 36.8 (Aug. 1988 [T-MTT]): 1265-1271.

This paper presents an attempt to calculate the characteristics of a shielded microstrip line with finite metallization thickness by the point matching method (PMM). Numerical results are presented in order to assert the validity of this approach in cases of large values of strip width to thickness ratio. It is found that an increase in the strip thickness is always associated with difficulties in convergence. This can be easily recognized if the field distribution is taken into account.

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